

TSMC-03-49



April 15, 2004

To: Commissioner for Patents
P.O.Box 1450
Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572
28 Davis Avenue
Poughkeepsie, N.Y. 12603

Subject: | Serial No. 10/772,938 02/05/04 |
Chii-Ming Wu et al.
METHOD OF FORMING METAL SILICIDE
| _____ |

INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation
In An Application.

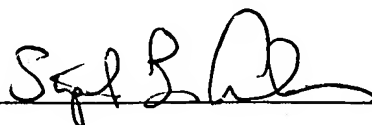
The following Patents and/or Publications are submitted to
comply with the duty of disclosure under CFR 1.97-1.99 and
37 CFR 1.56.

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being
deposited with the United States Postal Service as first class
mail in an envelope addressed to: Commissioner for Patents,
P.O. Box 1450, Alexandria, VA 22313-1450, on April 26, 2004.

Stephen B. Ackerman, Reg.# 37761

Signature/Date

 4/26/04

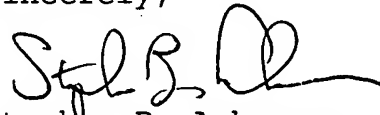
U.S. Patent 6,468,901 to Maa et al., "Nickel Silicide Including Iridium for Use in Ultra-Shallow Junctions with High Thermal Stability and Method of Manufacturing the Same," discloses an integrated circuit device, and a method of manufacturing the same, including nickel silicide on a silicon substrate fabricated with an iridium interlayer.

U.S. Patent 6,346,477 to Kaloyeros et al., "Method of Interlayer Mediated Epitaxy of Cobalt Silicide from Low Temperature Chemical Vapor Deposition of Cobalt," discusses a process for the preparation of cobalt disilicide films.

U.S. Patent 6,511,867 to Lowrey et al., "Utilizing Atomic Layer Deposition for Programmable Device," discloses an apparatus that sets and reprograms the state of programmable devices.

U.S. Patent 6,423,619 to Grant et al., "Transistor Metal Gate Structure that Minimizes Non-Planarity Effects and Method of Formation," discloses a metal gate structure formed by depositing a gate dielectric, a gate electrode, a stop layer, and a metal layer within a gate trench and removing the portions of the layers that lie outside the gate trench.

Sincerely,

A handwritten signature in dark ink, appearing to read "Stephen B. Ackerman", with a stylized flourish at the end.

Stephen B. Ackerman, Reg. #37761

Signature Number

10/772,938

Chii-Ming Wu et al.

02/05/04

Group 21 Unit

(Use several sheets if necessary)

APR 29 2004

U. S. PATENT & TRADEMARK OFFICE

SENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

OTHER DOCUMENTS (Including Author, Title, Date, Portion or Pages, Etc.)

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.